TOSHIBA Field Effect Transistor Silicon P, N Channel MOS Type (U-MOS IV / U-MOS III)

TPCP8403

Portable Equipment Applications Motor Drive Applications DC-DC Converter Applications

- Lead(Pb)-Free
- Low drain-source ON resistance : P Channel R_{DS} (ON) = 55 m Ω (typ.) N Channel R_{DS} (ON) = 31 m Ω (typ.)
- High forward transfer admittance : P Channel $|Y_{fs}| = 6.0 \text{ S} \text{ (typ.)}$
- N Channel $|Y_{fs}| = 8.6 \text{ S (typ.)}$
- Low leakage current : P Channel $I_{DSS} = -10 \ \mu A \ (V_{DS} = -40 \ V)$ N Channel $I_{DSS} = 10 \ \mu A \ (V_{DS} = 40 \ V)$
- Enhancement mode : P Channel V_{th} = -0.8 to -2.0 V (V_{DS} = -10 V, I_D = -1mA) N Channel V_{th} = 1.3 to 2.5 V (V_{DS} = 10 V, I_D = 1mA)

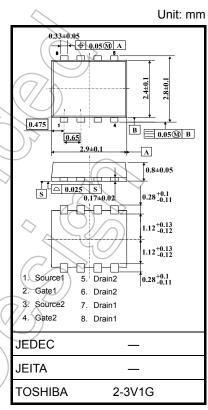
Absolute Maximum Ratings (Ta = 25°C)

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Characteristics		Symbol	Rating		Unit
Drain-source voltage		V _{DSS}	-40	40	V
Drain-gate vo	ltage (R _{GS} = 20 kΩ)	V _{DGR}	-40	40	V
Gate-source	voltage	V _{GSS}	±20	±20	×
Drain	DC (Note 1)	I _D	-3.4	4.7	$\langle \ $
current	Pulse (Note 1)	IDP	-13.6	18.8	A
Drain power dissipation	Single-device operation (Note 3a)	P _{D (1)}	1.48	1.48	
(t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	PD (2)	1.23	1.23	w
Drain power dissipation (t = 5 s) (Note 2b)	Single-device operation (Note 3a)	PD (1)	0.58	0.58	Vy >
	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.36	0.36	r
Single pulse avalanche energy (Note 4)		Eas	5.5	10.6	mJ
Avalanche current		I _{AR}	-3.4	4.7	А
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)		E _{AR}	0.12		mJ
Channel temperature		Tch	150		°C
Storage temperature range		Tstg	_55~150		°C

Note: For Notes 1 to 6, refer to the next page.

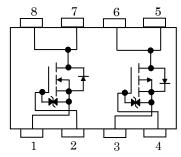
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with caution.

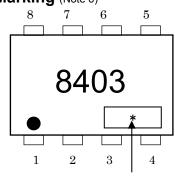


Weight: 0.017 g (typ.)

Circuit Configuration



Marking (Note 6)



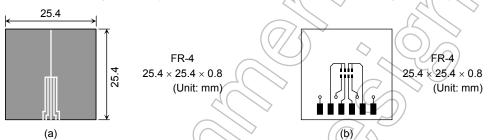
Lot No.

Thermal Characteristics

Chara	Symbol	Max	Unit		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	84.5	°C/W	
(t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	101.6		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	215.5	°C/W	
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	347.2	0/10	

Note 1: The channel temperature should not exceed 150°C during use,

Note 2: (a) Device mounted on a glass-epoxy board (a) (b) Device mounted on a glass-epoxy board (b)



Note 3: a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is only applied to one device.)

- b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is evenly applied to both devices.)
- Note 4: P Channel: $V_{DD} = 25 \text{ V}, T_{ch} = 25^{\circ}\text{C}$ (initial), L = 0.5 mH, $R_G = 25 \Omega$, $I_{AR} = -3.4 \text{ A}$ N Channel: $V_{DD} = 25 \text{ V}, T_{ch} = 25^{\circ}\text{C}$ (initial), L = 0.5 mH, $R_G = 25 \Omega$, $I_{AR} = 4.7 \text{ A}$
- Note 5: Repetitive rating: pulse width limited by maximum channel temperature
- Note 6: on the lower left of the marking indicates Pin 1.

※ Weekly code (3 digits):

(01 for the first week of the year, continuing up to 52 or 53)

Year of manufacture

Week of manufacture

(The last digit of the calendar year)

P-ch

Electrical Characteristics (Ta = 25°C)

Ch	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS}=\pm 16~V,~V_{DS}=0~V$	_	_	±10	μA
Drain cut-off curr	rent	I _{DSS}	$V_{DS} = -40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	\mathcal{F}	—	10	μA
Drain-source breakdown voltage		V (BR) DSS	$I_D = -10$ mA, $V_{GS} = 0$ V	-40	1		V
		V (BR) DSX	$I_D = -10$ mA, $V_{GS} = 20$ V	-25_))		v
Gate threshold v	oltage	V _{th}	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.8	_	-2.0	V
Drain-source ON resistance		Rea (on)	$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -1.7 \text{ A}$	A	80	105	mΩ
		R _{DS (ON)}	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -1.7 \text{ A}$		55	70	
Forward transfer admittance		Y _{fs}	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1.7 \text{ A}$	3.0	6.0	_	S
Input capacitance	e	C _{iss}		_	680		
Reverse transfer capacitance		C _{rss}	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	—	80	¢	pF
Output capacitance		C _{oss}			100	> -	
Switching time	Rise time	tr	$0 V - I_D = -1.7A$ $-10 V - I_D = -0 OUT$		8.5) —	
	Turn-on time	t _{on}			16		ns
	Fall time	t _f			16		115
	Turn-off time	toff	Duty $\leq 1\%$, t _w = 10 µs) _	120		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -32 \text{ V}, \text{ V}_{GS} = -10 \text{ V},$	_	15	_	
Gate-source charge 1		Q _{gs1}	$I_D = -3.4 \text{ A}$	_	2	_	nC
Gate-drain ("miller") charge		Qgd	\land	_	3.5	_	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol Test Condition	Min	Тур.	Max	Unit
Drain reverse current Pulse (Note 1)	IDRP -	_	_	-13.6	А
Forward voltage (diode)	V_{DSF} $I_{\text{DR}} = -3.4 \text{ A}, V_{\text{GS}} = 0 \text{ V}$			1.2	V

N-ch

Electrical Characteristics (Ta = 25°C)

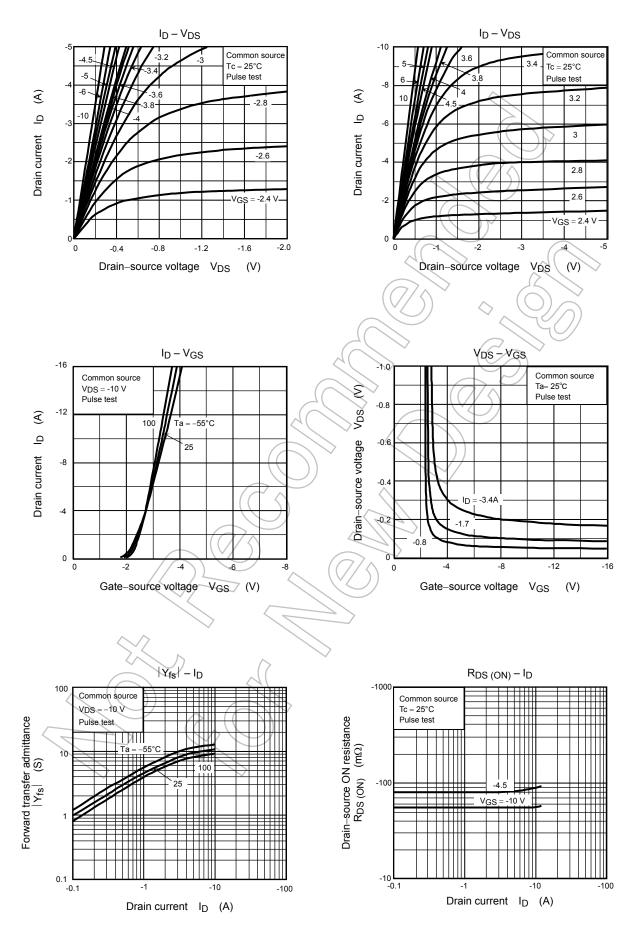
Cha	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V		_	±10	μA
Drain cut-off curre	ent	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V	X	_	10	μA
Drain-source brea	akdown	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	(40	$\langle \rangle$	_	V
voltage		V (BR) DSX	I _D = 10 mA, V _{GS} = -20 V	15	2_	—	v
Gate threshold vo	bltage	V _{th}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	1.3	_	2.5	V
Drain-source ON resistance		Ppg (on)	V _{GS} = 4.5 V, I _D = 2.4 A	\mathcal{I}	43	60	mΩ
Diam-source ON	resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 2.4 A	- <	31	40	11122
Forward transfer admittance		Y _{fs}	V _{DS} = 10 V, I _D = 2.4 A	4.3	8.6	Ι	S
Input capacitance		C _{iss}	$\langle \langle \rangle$	_	770	Á	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		70		pF
Output capacitance		Coss	(\checkmark)	_((105	_	
Switching time	Rise time	tr	$V_{GS} = 2.4A$		8	_	
	Turn-on time	t _{on}		2	15		ns
	Fall time	tf)_	9		115
	Turn-off time	toff	Duty \leq 1%, t _w = 10 µs		70		
Total gate charge (gate-source plus gate-drain)		Qg	\sim	—	16		
Gate-source charge 1 Qgs1		Qgs1	V _{DD} ≈ 32,V, V _{GS} = 10 V, I _D = 4.7 A	—	2.5	—	nC
Gate-drain ("miller") charge		Qgd		—	4	—	

Source-Drain Ratings and Characteristics (Ta = 25°C)

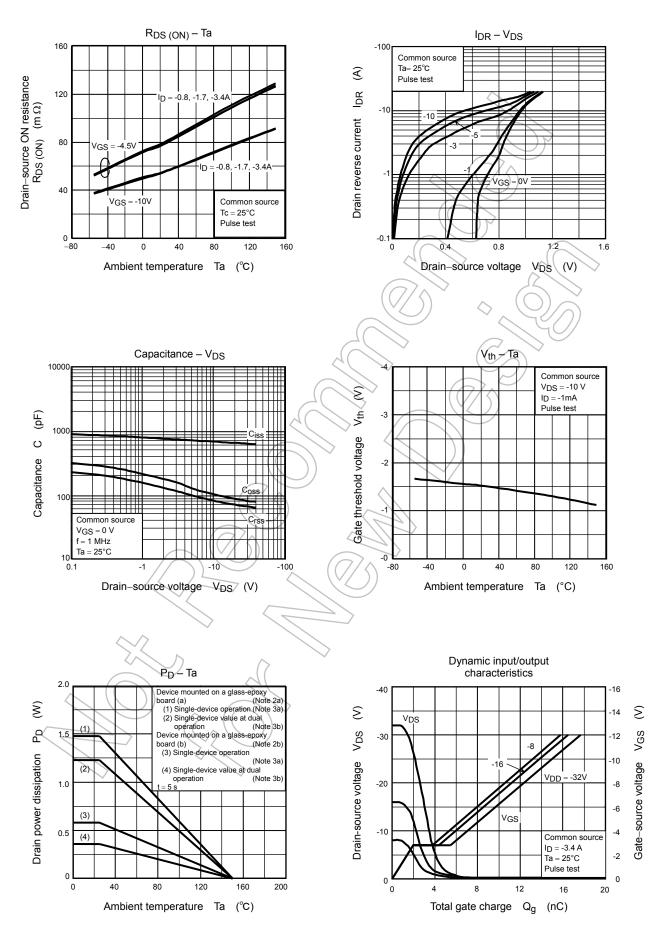
Characteristics	Symbol Test Condition	Min	Тур.	Max	Unit
Drain reverse current Pulse (Note 1)	I _{DRP} —	_		18.8	А
Forward voltage (diode)	V _{DSF} I _{DR} = 4.7 A, V _{GS} = 0 V	—	_	-1.2	V



P-ch

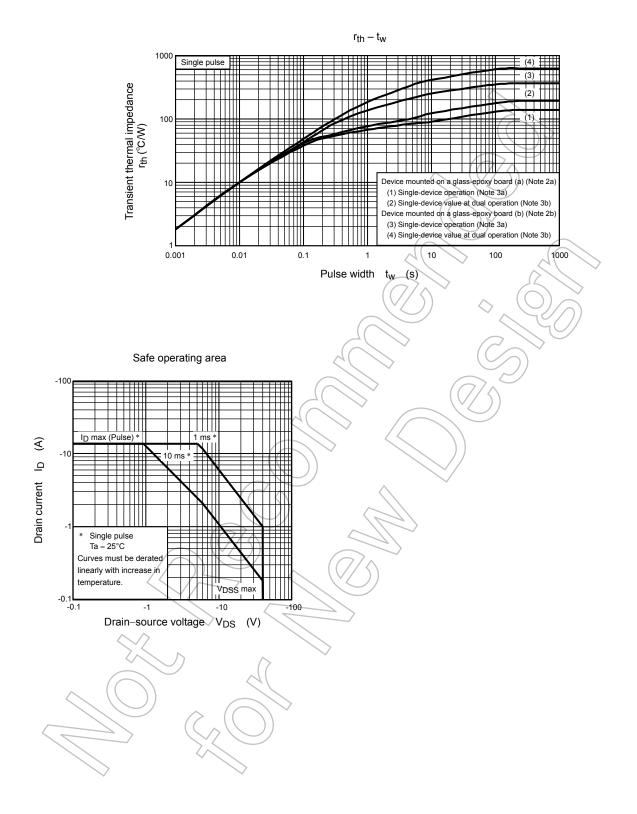


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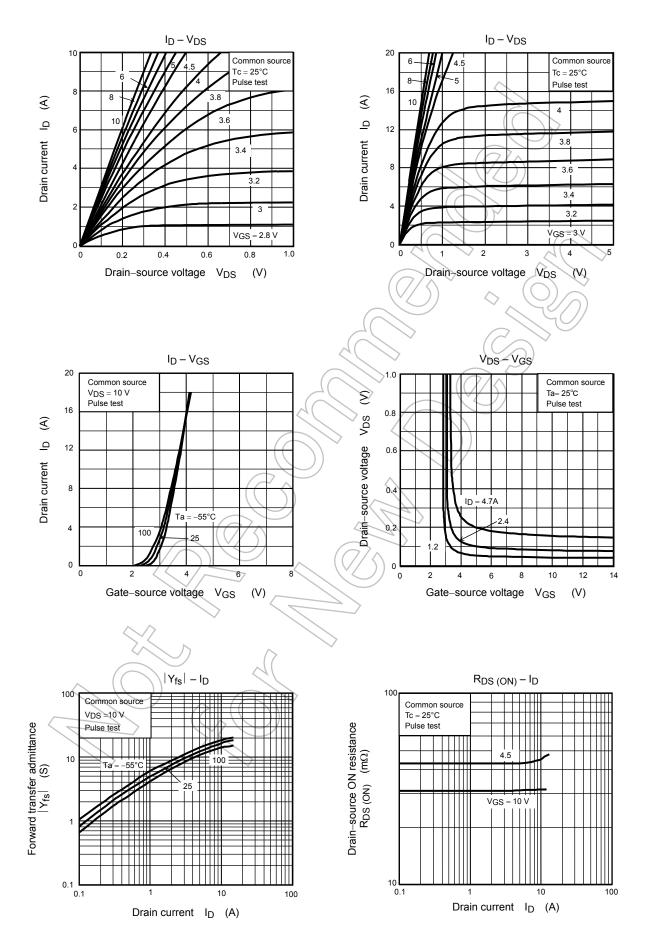


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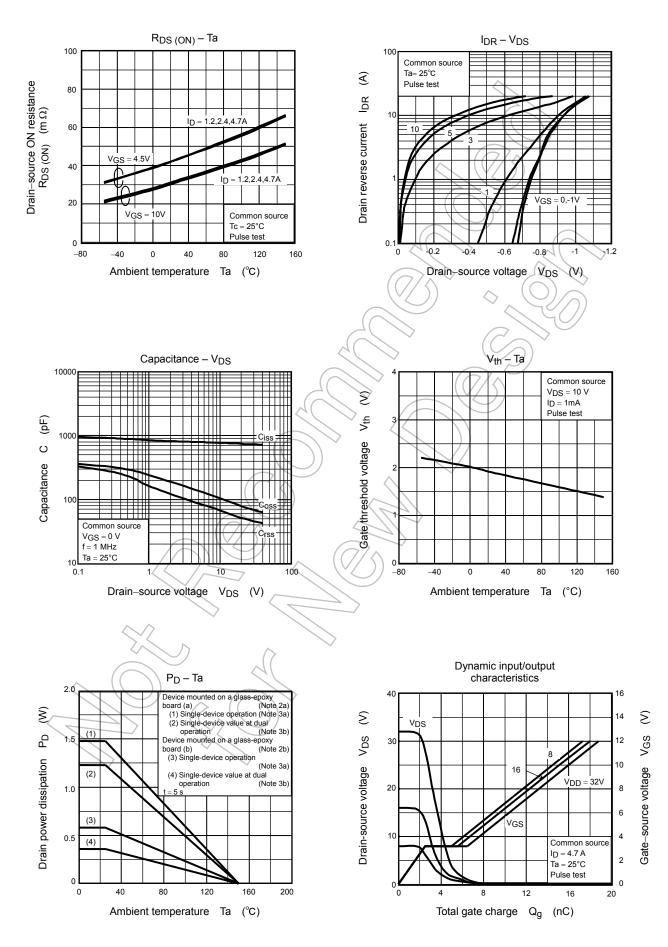
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N-ch

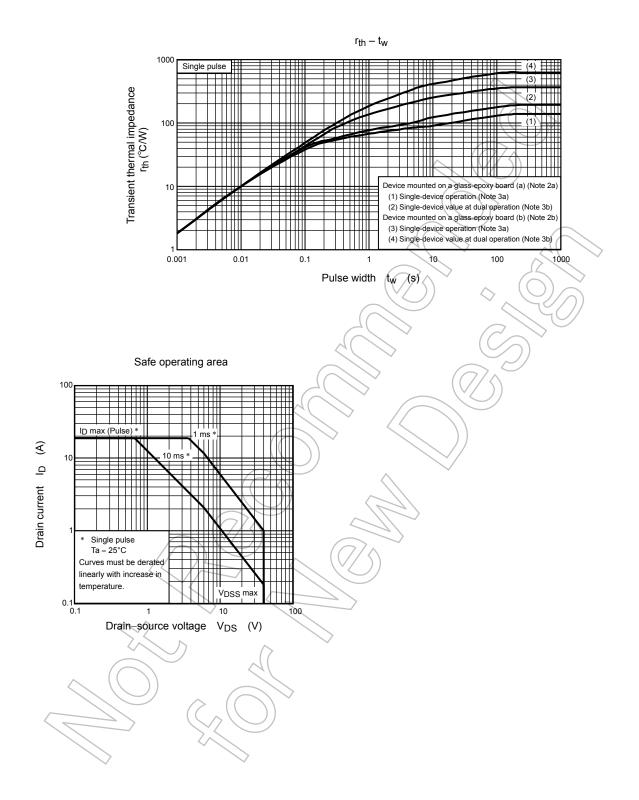


N-ch



N-ch

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